

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/798,133	ONOUE ET AL.	
Examiner	Art Unit	
Benjamin Kurtz	1723	

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	SEAR	CHED	
Class	Subclass	Date	Examiner
210	232,233 238,435 443,444	5/8/2006	вк
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East Search	5/8/2006	вк		
Inventor Name Search	5/8/2006	вк		